

Resource Summary Report

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Hitachi: 3400N Environmental Scanning Electron Microscope

RRID:SCR_020013

Type: Tool

Proper Citation

Hitachi: 3400N Environmental Scanning Electron Microscope (RRID:SCR_020013)

Resource Information

URL: <https://cmrf.research.uiowa.edu/hitachi-s-3400n>

Proper Citation: Hitachi: 3400N Environmental Scanning Electron Microscope (RRID:SCR_020013)

Description: Hitachi S-3400N SEM is a high performance, user-friendly scanning electron microscope. Features include: VP-mode that allows microscopy of wet, oily and non-conductive samples in their natural state without the need of conventional sample preparation.

Resource Type: instrument resource

Keywords: Hitachi, Environmental Scanning Electron Microscope, Instrument Equipment, USEDit

Availability: Commercially available

Specification URL: https://raw.githubusercontent.com/SciCrunch/RRID-Instruments/main/PDF/SCR_020013.pdf

Resource Name: Hitachi: 3400N Environmental Scanning Electron Microscope

Resource ID: SCR_020013

Alternate IDs: Model_Number_3400N

Record Creation Time: 20220129T080348+0000

Record Last Update: 20260801T190637+0000

Ratings and Alerts

No rating or validation information has been found for Hitachi: 3400N Environmental Scanning Electron Microscope.

No alerts have been found for Hitachi: 3400N Environmental Scanning Electron Microscope.

Data and Source Information

Source: [SciCrunch Registry](#)

Usage and Citation Metrics

We have not found any literature mentions for this resource.